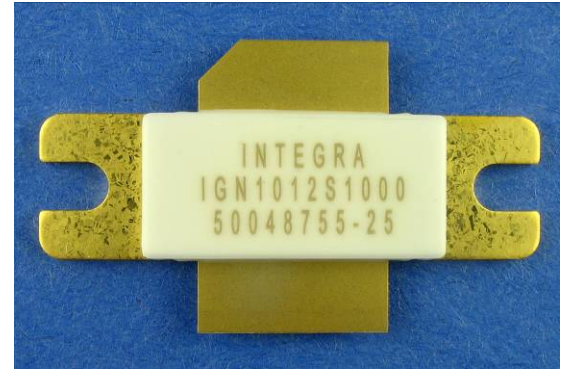


L-Band Avionics Transistor – GaN

- GaN on SiC HEMT Technology
- $P_{OUT-PK} = 1000W @ 32\mu s/2\% / 50V$
- 1.025-1.150GHz Instantaneous Operating Frequency Range
- Internal Impedance Pre-matched Device
- Depletion Mode Device
- Negative Gate Voltage and Bias Sequencing Required
- Specified For Use Under Class AB Operation
- Metal Based Package Sealed With Ceramic-Epoxy Lid
- Gold Metallization System: Chip - Wire Bond - Package
- Package Size: W=1.340" (34.04mm), L=0.385" (9.78mm)
- 100% High Power RF Tested in Fixed Tuned RF Test Fixture



| PARAMETER | SYM | MIN | TYP | MAX | UNITS | TEST CONDITIONS |
|-------------------------------------|-------------|-------|-------|-------|-------|---|
| DC ELECTRICAL SPECIFICATIONS | | | | | | |
| Drain Leakage Current | I_{D-OFF} | -- | -- | 4.0 | mA | $V_{DS}=50V, V_{GS}=-6V, T_{F1}, S1$ |
| Gate Threshold Voltage | V_{GS-TH} | -- | -2.8 | -- | V | $V_{DS}=50V, I_D=75mA, T_{F1}, BD$ |
| RF ELECTRICAL SPECIFICATIONS | | | | | | |
| Input Return Loss | IRL | -18 | -14 | -10 | dB | POUT1, V1, I_{DQ1} , PW1, DF1, F1, F2, F3, $T_{F1}, S1$ |
| Power Input | PIN | 16.2 | 25.0 | 32.0 | W | POUT1, V1, I_{DQ1} , PW1, DF1, F1, F2, F3, $T_{F1}, S1$ |
| Power Gain | Gp | 15.0 | 16.0 | 17.5 | dB | POUT1, V1, I_{DQ1} , PW1, DF1, F1, F2, F3, $T_{F1}, S1$ |
| Drain Efficiency | N_D | 45 | 50 | 75 | % | POUT1, V1, I_{DQ1} , PW1, DF1, F1, F2, F3, $T_{F1}, S1$ |
| Pulse Amplitude Droop | D | -0.40 | -0.20 | +0.20 | dB | POUT1, V1, I_{DQ1} , PW1, DF1, F1, F2, F3, $T_{F1}, S1$ |
| Load Mismatch Stability | VSWR-S | 2:1 | -- | -- | -- | POUT1, V1, I_{DQ1} , PW1, DF1, F1, F2, F3, $T_{F1}, S1$ |
| Load Mismatch Tolerance | LMT | 3:1 | -- | -- | -- | POUT1, V1, I_{DQ1} , PW1, DF1, F1, F2, F3, $T_{F1}, S1$ |

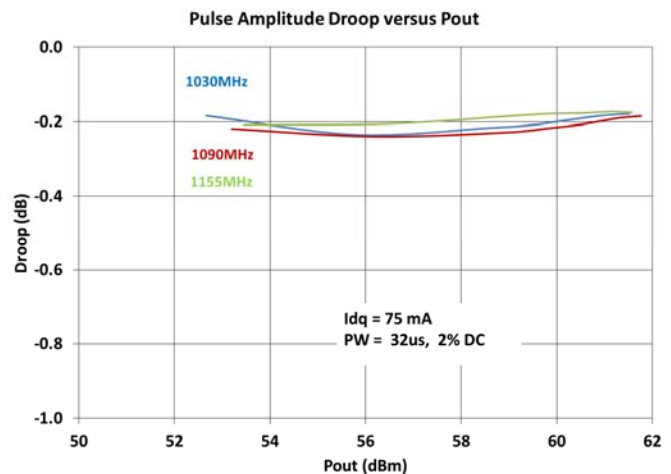
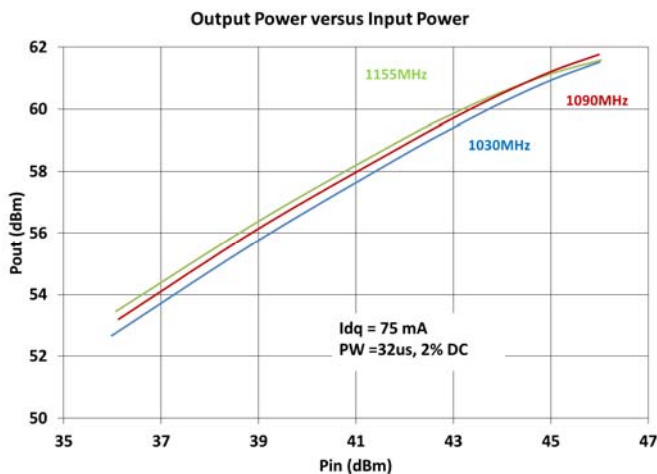
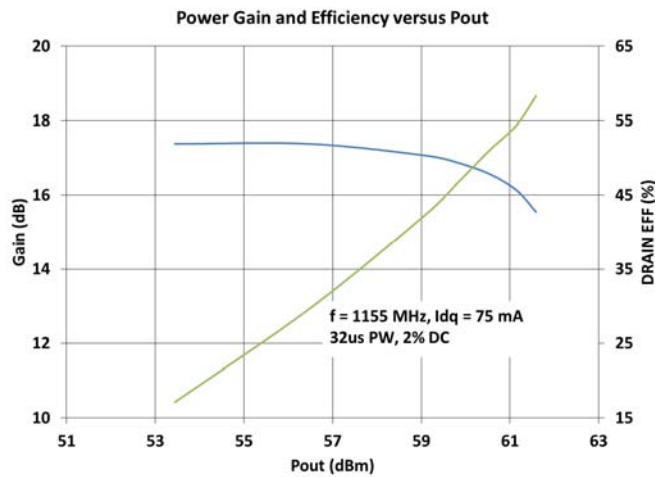
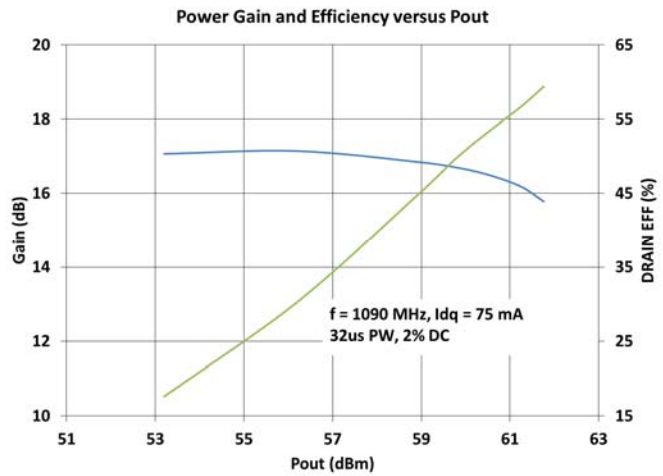
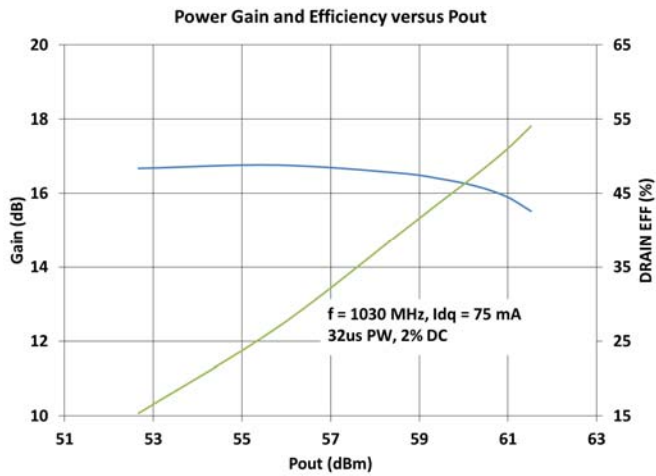
| DC & RF TEST CONDITIONS | SYM | MIN | NOM | MAX | UNITS | TEST CONDITIONS |
|---------------------------|-----------|-----|-------|-----|-------------|-----------------|
| Output Power 1 | POUT1 | -- | 1000 | -- | W | -- |
| Drain Supply Voltage 1 | V1 | -- | 50 | -- | V | -- |
| Quiescent Drain Current 1 | I_{DQ1} | 70 | 75 | 80 | mA | -- |
| Pulse Width 1 | PW1 | -- | 32 | -- | μs | -- |
| Duty Factor 1 | DF1 | -- | 2 | -- | % | -- |
| Frequency 1 | F1 | -- | 1.025 | -- | GHz | -- |
| Frequency 2 | F2 | -- | 1.090 | -- | GHz | -- |
| Frequency 3 | F3 | -- | 1.150 | -- | GHz | -- |
| Flange Temperature 1 | T_{F1} | 25 | 30 | 35 | $^{\circ}C$ | -- |

| PARAMETER | SYM | MIN | MAX | UNITS | SCREEN | CONDITIONS |
|--|--------------|-----|-------|--------------------|--------|--------------------------|
| MAXIMUM RATINGS | | | | | | |
| Drain-Source Voltage | V_{DS} | -- | 150 | V | BD | $T_F = 25^\circ\text{C}$ |
| Gate-Source Voltage | V_{GS} | -10 | 0 | V | BD | $T_F = 25^\circ\text{C}$ |
| Storage Temperature Range | T_{STG} | -55 | +150 | $^\circ\text{C}$ | BD | -- |
| Operating Junction Temperature | T_J | -55 | +200 | $^\circ\text{C}$ | BD | -- |
| PROCESS SPECIFICATIONS | | | | | | |
| DC Wafer Probe | -- | -- | -- | -- | 100% | Per Integra Spec |
| Wafer DC, RF Qualification | -- | -- | -- | -- | Q1 | Per Integra Spec |
| Wire Bond Strength | -- | -- | -- | -- | LM | Per Integra Spec |
| Pre-cap Visual Inspection | -- | -- | -- | -- | 100% | Per Integra Spec |
| Gross Leak Test – MIL-STD-750D | -- | -- | -- | -- | 100% | Method 1071.6 C |
| THERMAL RESISTANCE | | | | | | |
| Peak Thermal Resistance Per Rated RF Specification | $R_{TH(JC)}$ | -- | 0.056 | $^\circ\text{C/W}$ | BD | $T_F = 25^\circ\text{C}$ |
| SCREENING LEVELS | | | | | | |
| Screening Level 1 | S1 | 100 | -- | % | -- | -- |
| Parameter Qualified By Design | BD | -- | -- | -- | -- | -- |
| Parameter Qualified By 3 Pieces (min) Per Wafer | Q1 | -- | -- | -- | -- | -- |
| Parameter Qualified By Assembly Line Monitor | LM | -- | -- | -- | -- | -- |

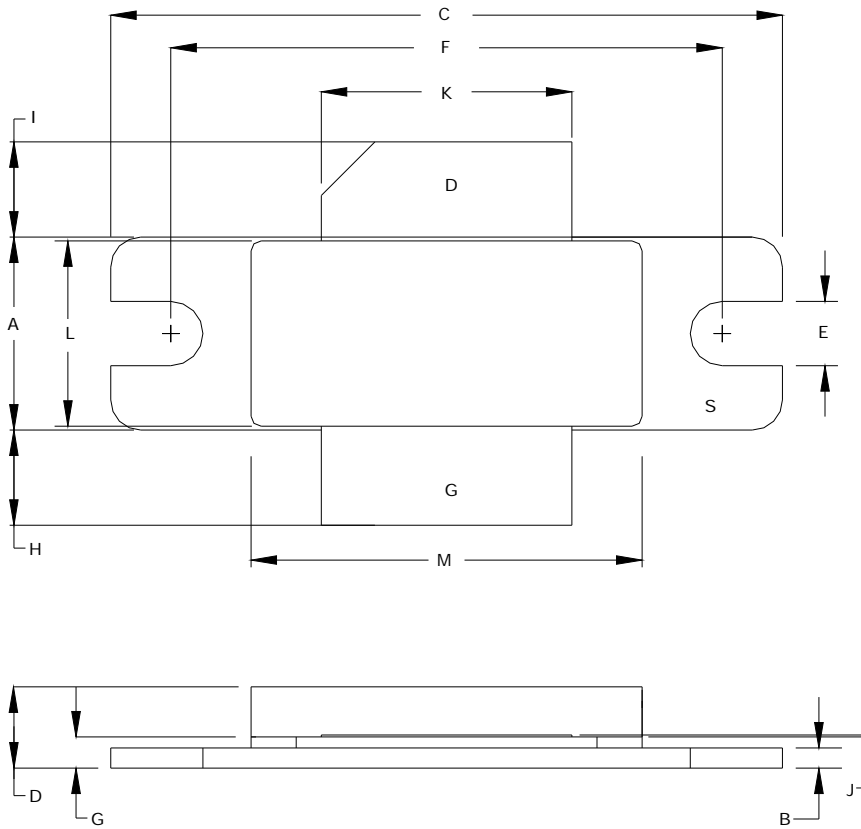
| RF TEST FIXTURE – BROADBAND | | |
|--|------------------|------------------|
| ▶ Broadband RF Test Fixture. Provides Device Impedance Matching to 50Ω Across the Rated Operating Frequency Range. | | |
| ▶ Electronic CAD Drawing File Available Upon Request. Includes Circuit Dimensions and Parts List. | | |
| ▶ Reference Design PCB: Rogers RTD6006-02511, DK=6.15. | | |
| FREQUENCY (GHz) | $Z_{IF}(\Omega)$ | $Z_{OF}(\Omega)$ |
| 1.025 | 3.8 – j 1.1 | 1.00 + j 0.05 |
| 1.090 | 4.1 – j 0.3 | 0.90 + j 0.10 |
| 1.150 | 4.4 + j 0.5 | 0.65 + j 0.25 |
| Impedance Definition | | |

| DC BIAS SEQUENCING | |
|--|--|
| Turn ON GaN Device | Turn OFF GaN Device |
| <ol style="list-style-type: none"> 1. RF Power OFF 2. Set VGS = -5V (Negative Voltage to pinch off) 3. Measure VDS impedance, should be pinched off. 4. Turn ON VDD voltage. 5. Slowly increase VGS until bias current IDQ is set. 6. Turn ON RF Power | <ol style="list-style-type: none"> 1. Turn OFF RF Power 2. Turn OFF VDD voltage 3. After VDD is discharged, set VGS = -5V 4. Turn OFF VGS voltage. |

TYPICAL PERFORMANCE



PACKAGE OUTLINE DRAWING



| DIM | INCHES | | MILLIMETERS | |
|-----|--------|-------|-------------|-------|
| | MIN | MAX | MIN | MAX |
| A | 0.380 | 0.390 | 9.65 | 9.90 |
| B | 0.035 | 0.045 | 0.89 | 1.14 |
| C | 1.335 | 1.345 | 33.90 | 34.16 |
| D | 0.139 | 0.166 | 3.53 | 4.21 |
| E | 0.123 | 0.133 | 3.12 | 3.37 |
| F | 1.095 | 1.105 | 27.81 | 28.06 |
| G | 0.057 | 0.067 | 1.44 | 1.70 |
| H | 0.170 | 0.210 | 4.32 | 5.33 |
| I | 0.170 | 0.210 | 4.32 | 5.33 |
| J | 0.003 | 0.006 | 0.08 | 0.15 |
| K | 0.495 | 0.505 | 12.57 | 12.82 |
| L | 0.364 | 0.374 | 9.24 | 9.49 |
| M | 0.772 | 0.788 | 19.60 | 20.01 |

| PIN SCHEDULE | |
|--------------|--------|
| D | DRAIN |
| S | SOURCE |
| G | GATE |

DEFINITIONS**DATA SHEET STATUS**

| | |
|---------------------------|---|
| Proposed Specification | This data sheet contains proposed specifications. |
| Preliminary Specification | This data sheet contains specifications based on preliminary measurements and data. |
| Product Specification | This data sheet contains final product specifications. |

MAXIMUM RATINGS

Stress above one or more of the maximum ratings may cause permanent damage to the device. These are maximum ratings only operation of the device at these or at any other conditions above those given in the characteristics sections of the specification is not implied. Exposure to maximum values for extended periods of time may affect device reliability.

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